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Bib Data Sheet

CONFIRMATION NO. 5606

SERIAL NUMBER 10/084,338	FILING DATE 02/28/2002 RULE	CLASS 714	GROUP ART UNIT 2133	ATTORNEY DOCKET NO. 50090-478	
APPLICANTS Yukikazu Matsuo, Hyogo, JAPAN; Yoshihiro Nagura, Tokyo, JAPAN; ** CONTINUING DATA ***** <i>NONE</i> ** FOREIGN APPLICATIONS ***** <i>YES</i> JAPAN 2001-224899 07/25/2001 <i>6/24/04</i>					
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 03/25/2002					
Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met After Allowance Verified and Acknowledged Examiner's Signature <i>[Signature]</i> Initials <i>[Initials]</i>		STATE OR COUNTRY JAPAN	SHEETS DRAWING 9	TOTAL CLAIMS 8	INDEPENDENT CLAIMS 3
ADDRESS McDermott, Will & Emery 600 13th Street, N.W. Washington, DC 20005-3096					
TITLE Testing device of semiconductor integrated circuit and test method therefor					
FILING FEE RECEIVED 1020	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		